

L Number	Hits	Search Text	DB	Time stamp
1	66827	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically thickness	EPO; JPO; IBM_TDB	2003/02/04 14:46
2	319949		EPO; JPO; IBM_TDB	2003/02/04 14:46
3	290	(zero or zeroeth) with order with diffraction	EPO; JPO; IBM_TDB	2003/02/04 14:46
4	516383	transmit or transmitting or transmission	EPO; JPO; IBM_TDB	2003/02/04 14:46
5	130914	reflect or reflecting or reflection	EPO; JPO; IBM_TDB	2003/02/04 14:46
6	65920	parameter or parametric	EPO; JPO; IBM_TDB	2003/02/04 14:47
7	1016834	substrate or wafer or film	EPO; JPO; IBM_TDB	2003/02/04 14:47
8	3614	(interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness	EPO; JPO; IBM_TDB	2003/02/04 14:47
9	1	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)	EPO; JPO; IBM_TDB	2003/02/04 14:47
11	0	((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film)) and (parameter or parametric)	EPO; JPO; IBM_TDB	2003/02/04 14:47
10	1	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film)	EPO; JPO; IBM_TDB	2003/02/04 14:47
-	129	(356/503).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	107	(356/504).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	243	(356/630).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	287	(356/632).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	190	(250/559.27).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	90	(250/559.28).CCLS.	USPAT; US-PGPUB	2003/02/04 14:31
-	476804	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically thickness	USPAT; US-PGPUB	2003/02/04 14:46
-	851459		USPAT; US-PGPUB	2003/02/04 14:46
-	1672	(zero or zeroeth) with order with diffraction	USPAT; US-PGPUB	2003/02/04 14:46
-	779773	transmit or transmitting or transmission	USPAT; US-PGPUB	2003/02/04 14:46
-	339521	reflect or reflecting or reflection	USPAT; US-PGPUB	2003/02/04 14:46
-	468229	parameter or parametric	USPAT; US-PGPUB	2003/02/04 14:46
-	835088	substrate or wafer or film	USPAT; US-PGPUB	2003/02/04 14:47
-	147926	(interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness	USPAT; US-PGPUB	2003/02/04 14:47

-	514	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction))	USPAT; US-PGPUB	2003/02/04 14:47
-	462	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film)	USPAT; US-PGPUB	2003/02/04 14:47
-	205	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film) and (parameter or parametric)	USPAT; US-PGPUB	2003/02/04 14:47
-	176	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film) and (parameter or parametric)) and (transmit or transmitting or transmission)	USPAT; US-PGPUB	2003/02/04 14:36
-	152	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film) and (parameter or parametric)) and (transmit or transmitting or transmission)) and (reflect or reflecting or reflection)	USPAT; US-PGPUB	2003/02/04 14:37
-	34	356/\$.ccls. and (((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film) and (parameter or parametric)) and (transmit or transmitting or transmission)) and (reflect or reflecting or reflection))	USPAT; US-PGPUB	2003/02/04 14:37
-	11	250/\$.ccls. and (((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and thickness) and ((zero or zeroeth) with order with diffraction)) and (substrate or wafer or film) and (parameter or parametric)) and (transmit or transmitting or transmission)) and (reflect or reflecting or reflection))	USPAT; US-PGPUB	2003/02/04 14:38